	Enrollr	nent No:		Exam Seat No:				
-	12111 ()111	nent 140.		UNIVERSI		_		
	Summer Examination-2017							
i	Subject	t Name: (CMOS VLSI Design					
i	Subject Code: 5TE01CVD1			Branch: M.Tech (VESD)				
	Semest	er: 1	Date: 20/03/2017	Time: 10:30 To 01:3	0 Marks: 70			
	Instruc	etions:						
•	(1)	Use of P	rogrammable calculator an	<u> </u>	-			
	(2) Instructions written on main answer book are strictly to be obeyed.							
	(3) Draw neat diagrams and figures (if necessary) at right places.(4) Assume suitable data if needed.							
	(4)	Assume	sultable data il fleeded.					
			SE	CTION – I				
Q-1	Define the following terms							
	a.	NM_H	.			(07)		
	b.	Transist	or sizing.					
	c.		old Voltage.					
	d.		ne.					
	e.	L						
	f.	•	ic Power Consumption.					
	g.	Power I	Delay Product.					
Q-2		Attemn	ot all questions			(14)		
~ -	(a)	_	the minimization of RC et	ffect in CMOS inverter cha	ain.	(= -)		
	(b)		the Series and Parallel CM					
				OR				
Q-2		_	ot all questions			(14)		
	(a)		a transistor-level schema (B+C) D)'.	atic for a compound C	MOS logic gate for			
	(b)	Design	and explain 3-input CMOS	S Ex-OR. How many trans	istors are required?			
Q-3		Attemp	ot all questions			(14)		

Q-2

Q-3

- (a)
- Compare CMOS and NMOS.
 Explain Body effect. Explain how Body effect affects the threshold voltage. **(b)**

OR

Q-3 **Attempt all questions**

(14)

- Explain the Transmission gate and the tri-state inverter Explain the fringing effects in MOS device. (a)
- **(b)**



SECTION – II

Q-4		Define the following terms	(07)		
	a.	Tri-state logic			
	b.	Bi-directional Pads			
	c.	Serial Multiplier			
	d.	Routing capacitance of MOS			
	e.	Pass transistor			
	f.	Latch			
	g.	Charge sharing			
Q-5		Attempt all questions	(14)		
	(a)	Derive the capacitances of three regions of operation of MOS device.	` ,		
	(b)	Write note on CMOS Domino logic			
		OR			
Q-5		Attempt all questions			
	(a)	Draw and explain Cascade Voltage Switch logic (CVSL)	(14)		
	(b)	Explain Pseudo 4-phase memory structures.			
Q-6		Attempt all questions	(14)		
•	(a)	Explain in detail Boundary-scan testing.	()		
	(b)	Explain the design of Ripple Carry Binary Asynchronous Counter.			
		OR			
Q-6		Attempt all Questions	(14)		
Q-0	(a)	Explain the design of Wallace tree multiplier circuit.	(17)		
	(a) (b)	Explain the basic Dynamic MOS RAM Cell.			
	(0)	Explain the basic Dynamic Wob Kriw Cen.			

